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144 027002

Attorney Docket Number 5347-208

Serial No.
09/891-552

Applicants: Luckovsky et al.

Filing Date: June 25, 2001

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U. S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation Yes No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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| Q4 | 1. Gordon et al., "Chemical Vapor Deposition and Properties of Amorphous Aluminum Oxide Films," Material Research Society Symposium Proceedings, 446, December 2-4, 1996, 383-388. |
| Q4 | 2. Hauser et al., "Characterization of Ultra-Thin Oxides Using Electrical C-V and I-V Measurements," Characterization and Metrology for ULSI Technology: 1998 International Conference, CP449, 235-239. |
| Q4 | 3. Luckovsky et al., "Minimization of Mechanical and Chemical Strain at Dielectric-Semiconductor and Internal Dielectric Interfaces in Stacked Gate Dielectrics for Advanced CMOS Devices," Characterization and Metrology for ULSI Technology: 2000 International Conference, CP550, 154-158. |
| Q4 | 4. Rayner et al., "Spectroscopic Evidence for a Network Structure in Plasma-Deposited Ta_2O_5 Films for Microelectronic Applications," Characterization and Metrology for ULSI Technology: 2000 International Conference, CP550, June 26-29, 2000, 149-153. |
| Q4 | 5. Schroder, "Oxide and Interface Trapped Charges, Oxide Integrity," Semiconductor Material and Device Characterization, Second Edition, 1998, 337-419. |
| Q4 | 6. Vickridge et al., "Spaces: A PC Implementation of the Stochastic Theory of Energy Loss for Narrow-Resonance Depth Profiling," Nuclear Instruments and Methods in Physics Research, B45, 1990 6-11. Presented at Proceedings of the Ninth International Conference on Ion Beam Analysis, June 26-30, 1989. |

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